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Details

Product Status	Obsolete
Core Processor	HCS12
Core Size	16-Bit
Speed	25MHz
Connectivity	CANbus, EBI/EMI, SCI, SPI
Peripherals	POR, PWM, WDT
Number of I/O	60
Program Memory Size	96KB (96K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4K x 8
Voltage - Supply (Vcc/Vdd)	2.35V ~ 5.5V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	80-QFP
Supplier Device Package	80-QFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s12c96mfue

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http://freescale.com/

A full list of family members and options is included in the appendices.

The following revision history table summarizes changes contained in this document.

This document contains information for all constituent modules, with the exception of the S12 CPU. For S12 CPU information please refer to the CPU S12 Reference Manual.

Revision History

Date	Revision Level	Description
June, 2005	01.14	New Book
July, 2005	01.15	Removed 16MHz option for 128K, 96K and 64K versions Minor corrections following review
Oct, 2005	01.16	Added outstanding flash module descriptions Added EPP package options Corrected and Enhanced recommended PCB layouts
Dec, 2005	01.17	Added note to PIM block diagram figure
Dec, 2005	01.18	Added PIM rerouting information to 80-pin package diagram
Jan, 2006	01.19	Modified LVI levels in electrical parameter section Corrected TSCR2 typo in timer register listing
Mar, 2006	01.20	Cleaned up Device Overview Section
May, 2006	01.21	Added 0M66G to PartID table Added units to MSCAN timing parameter table Corrected missing overbars on pin names
Dec, 2006	01.22	Corrected CRGFLG contents in register summary Removed non existing part number options Removed unintended symbol fonts from table A6
May, 2007	01.23	Updated ATD section Corrected typos
May, 2010	01.24	Updated TIM section



Chapter 1 MC9S12C and MC9S12GC Device Overview (MC9S12C128)



4.3.2.4 Data Direction Register B (DDRB)

Module Base + 0x0003

Starting address location affected by INITRG register setting.



Read: Anytime when register is in the map

Write: Anytime when register is in the map

This register controls the data direction for port B. When port B is operating as a general-purpose I/O port, DDRB determines the primary direction for each port B pin. A 1 causes the associated port pin to be an output and a 0 causes the associated pin to be a high-impedance input. The value in a DDR bit also affects the source of data for reads of the corresponding PORTB register. If the DDR bit is 0 (input) the buffered pin input state is read. If the DDR bit is 1 (output) the associated port data register bit state is read.

This register is not in the on-chip memory map in expanded and special peripheral modes. Therefore, these accesses will be echoed externally. It is reset to 0x00 so the DDR does not override the three-state control signals.

Table 4-4. DDRB Field Descriptions

Field	Description
7:0 DDRB	Data Direction Port B0 Configure the corresponding I/O pin as an input1 Configure the corresponding I/O pin as an output



9.6 Interrupts

The interrupts/reset vectors requested by the CRG are listed in Table 9-15. Refer to the device overview chapter for related vector addresses and priorities.

Interrupt Source	CCR Mask	Local Enable
Real-time interrupt	I bit	CRGINT (RTIE)
LOCK interrupt	I bit	CRGINT (LOCKIE)
SCM interrupt	I bit	CRGINT (SCMIE)

Table 9-15. CRG Interrupt Vectors

9.6.1 Real-Time Interrupt

The CRGV4 generates a real-time interrupt when the selected interrupt time period elapses. RTI interrupts are locally disabled by setting the RTIE bit to 0. The real-time interrupt flag (RTIF) is set to 1 when a timeout occurs, and is cleared to 0 by writing a 1 to the RTIF bit.

The RTI continues to run during pseudo-stop mode if the PRE bit is set to 1. This feature can be used for periodic wakeup from pseudo-stop if the RTI interrupt is enabled.

9.6.2 PLL Lock Interrupt

The CRGV4 generates a PLL lock interrupt when the LOCK condition of the PLL has changed, either from a locked state to an unlocked state or vice versa. Lock interrupts are locally disabled by setting the LOCKIE bit to 0. The PLL Lock interrupt flag (LOCKIF) is set to1 when the LOCK condition has changed, and is cleared to 0 by writing a 1 to the LOCKIF bit.

9.6.3 Self-Clock Mode Interrupt

The CRGV4 generates a self-clock mode interrupt when the SCM condition of the system has changed, either entered or exited self-clock mode. SCM conditions can only change if the self-clock mode enable bit (SCME) is set to 1. SCM conditions are caused by a failing clock quality check after power-on reset (POR) or low voltage reset (LVR) or recovery from full stop mode (PSTP = 0) or clock monitor failure. For details on the clock quality check refer to Section 9.4.4, "Clock Quality Checker." If the clock monitor is enabled (CME = 1) a loss of external clock will also cause a SCM condition (SCME = 1).

SCM interrupts are locally disabled by setting the SCMIE bit to 0. The SCM interrupt flag (SCMIF) is set to 1 when the SCM condition has changed, and is cleared to 0 by writing a 1 to the SCMIF bit.





Figure 10-5. MSCAN Control Register 1 (CANCTL1)

Read: Anytime

Write: Anytime when INITRQ = 1 and INITAK = 1, except CANE which is write once in normal and anytime in special system operation modes when the MSCAN is in initialization mode (INITRQ = 1 and INITAK = 1).

Field	Description
7 CANE	MSCAN Enable 0 MSCAN module is disabled 1 MSCAN module is enabled
6 CLKSRC	 MSCAN Clock Source — This bit defines the clock source for the MSCAN module (only for systems with a clock generation module; Section 10.4.3.2, "Clock System," and Section Figure 10-42., "MSCAN Clocking Scheme,"). 0 MSCAN clock source is the oscillator clock 1 MSCAN clock source is the bus clock
5 LOOPB	Loopback Self Test Mode — When this bit is set, the MSCAN performs an internal loopback which can be used for self test operation. The bit stream output of the transmitter is fed back to the receiver internally. The RXCAN input pin is ignored and the TXCAN output goes to the recessive state (logic 1). The MSCAN behaves as it does normally when transmitting and treats its own transmitted message as a message received from a remote node. In this state, the MSCAN ignores the bit sent during the ACK slot in the CAN frame acknowledge field to ensure proper reception of its own message. Both transmit and receive interrupts are generated. 0 Loopback self test disabled 1 Loopback self test enabled
4 LISTEN	 Listen Only Mode — This bit configures the MSCAN as a CAN bus monitor. When LISTEN is set, all valid CAN messages with matching ID are received, but no acknowledgement or error frames are sent out (see Section 10.4.4.4, "Listen-Only Mode"). In addition, the error counters are frozen. Listen only mode supports applications which require "hot plugging" or throughput analysis. The MSCAN is unable to transmit any messages when listen only mode is active. Normal operation Listen only mode activated
2 WUPM	 Wake-Up Mode — If WUPE in CANCTL0 is enabled, this bit defines whether the integrated low-pass filter is applied to protect the MSCAN from spurious wake-up (see Section 10.4.5.4, "MSCAN Sleep Mode"). 0 MSCAN wakes up on any dominant level on the CAN bus 1 MSCAN wakes up only in case of a dominant pulse on the CAN bus that has a length of T_{wup}

Table 10-2. CANCTL1 Register Field Descriptions



NOTE

Reading this register when in any other mode other than sleep or initialization mode may return an incorrect value. For MCUs with dual CPUs, this may result in a CPU fault condition.

Writing to this register when in special modes can alter the MSCAN functionality.

10.3.2.15 MSCAN Transmit Error Counter (CANTXERR)

This register reflects the status of the MSCAN transmit error counter.

7 6 5 4 з 2 1 0 R TXERR7 TXERR6 TXERR5 TXERR4 **TXERR3** TXERR2 TXERR1 TXERR0 W Reset: 0 0 0 0 0 0 0 0 = Unimplemented



Module Base + 0x000F

Figure 10-18. MSCAN Transmit Error Counter (CANTXERR)

Read: Only when in sleep mode (SLPRQ = 1 and SLPAK = 1) or initialization mode (INITRQ = 1 and INITAK = 1)

Write: Unimplemented

NOTE

Reading this register when in any other mode other than sleep or initialization mode, may return an incorrect value. For MCUs with dual CPUs, this may result in a CPU fault condition.

Writing to this register when in special modes can alter the MSCAN functionality.

NOTE

Reads of this register return the most recent value written. Reads do not necessarily return the value of the currently active duty due to the double buffering scheme.

Reference Section 12.4.2.3, "PWM Period and Duty," for more information.

NOTE

Depending on the polarity bit, the duty registers will contain the count of either the high time or the low time. If the polarity bit is 1, the output starts high and then goes low when the duty count is reached, so the duty registers contain a count of the high time. If the polarity bit is 0, the output starts low and then goes high when the duty count is reached, so the duty registers contain a count of the low time.

To calculate the output duty cycle (high time as a % of period) for a particular channel:

- Polarity = 0 (PPOLx = 0) Duty cycle = [(PWMPERx PWMDTYx)/PWMPERx] * 100%
- Polarity = 1 (PPOLx = 1) Duty cycle = [PWMDTYx / PWMPERx] * 100%
- For boundary case programming values, please refer to Section 12.4.2.8, "PWM Boundary Cases."

Module Base + 0x0018



Figure 12-27. PWM Channel Duty Registers (PWMDTY0)

Module Base + 0x0019

	7	6	5	4	3	2	1	0
R W	Bit 7	6	5	4	3	2	1	Bit 0
Reset	1	1	1	1	1	1	1	1

Figure 12-28. PWM Channel Duty Registers (PWMDTY1)

Module Base + 0x001A

	7	6	5	4	3	2	1	0
R W	Bit 7	6	5	4	3	2	1	Bit 0
Reset	1	1	1	1	1	1	1	1

Figure 12-29. PWM Channel Duty Registers (PWMDTY2)

NOTE

When queueing an idle character, return the TE bit to logic 1 before the stop bit of the current frame shifts out through the **Tx output** signal. Setting TE after the stop bit appears on **Tx output signal** causes data previously written to the SCI data register to be lost. Toggle the TE bit for a queued idle character while the TDRE flag is set and immediately before writing the next byte to the SCI data register.

NOTE

If the TE bit is clear and the transmission is complete, the SCI is not the master of the TXD pin



13.4.4 Receiver

Figure 13-12. SCI Receiver Block Diagram

13.4.4.1 Receiver Character Length

The SCI receiver can accommodate either 8-bit or 9-bit data characters. The state of the M bit in SCI control register 1 (SCICR1) determines the length of data characters. When receiving 9-bit data, bit R8 in SCI data register high (SCIDRH) is the ninth bit (bit 8).



Table 15-15. TSCR2 Field Descriptions

Field	Description
7 TOI	Timer Overflow Interrupt Enable 0 Interrupt inhibited. 1 Hardware interrupt requested when TOF flag set.
3 TCRE	 Timer Counter Reset Enable — This bit allows the timer counter to be reset by a successful output compare 7 event. This mode of operation is similar to an up-counting modulus counter. Counter reset inhibited and counter free runs. Counter reset by a successful output compare 7. Note: If TC7 = 0x0000 and TCRE = 1, TCNT will stay at 0x0000 continuously. If TC7 = 0xFFFF and TCRE = 1, TOF will never be set when TCNT is reset from 0xFFFF to 0x0000. Note: TCRE=1 and TC7!=0, the TCNT cycle period will be TC7 x "prescaler counter width" + "1 Bus Clock", for a more detail explanation please refer to Section 15.4.3, "Output Compare
2 PR[2:0]	Timer Prescaler Select — These three bits select the frequency of the timer prescaler clock derived from the Bus Clock as shown in Table 15-16.

PR2	PR1	PR0	Timer Clock
0	0	0	Bus Clock / 1
0	0	1	Bus Clock / 2
0	1	0	Bus Clock / 4
0	1	1	Bus Clock / 8
1	0	0	Bus Clock / 16
1	0	1	Bus Clock / 32
1	1	0	Bus Clock / 64
1	1	1	Bus Clock / 128

Table 15-16. Timer Clock Selection

NOTE

The newly selected prescale factor will not take effect until the next synchronized edge where all prescale counter stages equal zero.

15.3.2.12 Main Timer Interrupt Flag 1 (TFLG1)

Module Base + 0x000E



Read: Anytime



Chapter 16 Dual Output Voltage Regulator (VREG3V3V2) Block Description

16.2.3 V_{DD}, V_{SS} — Regulator Output1 (Core Logic)

Signals V_{DD}/V_{SS} are the primary outputs of VREG3V3V2 that provide the power supply for the core logic. These signals are connected to device pins to allow external decoupling capacitors (100 nF...220 nF, X7R ceramic).

In Shutdown Mode an external supply at V_{DD}/V_{SS} can replace the voltage regulator.

16.2.4 V_{DDPLL}, V_{SSPLL} — Regulator Output2 (PLL)

Signals V_{DDPLL}/V_{SSPLL} are the secondary outputs of VREG3V3V2 that provide the power supply for the PLL and oscillator. These signals are connected to device pins to allow external decoupling capacitors (100 nF...220 nF, X7R ceramic).

In Shutdown Mode an external supply at V_{DDPLL}/V_{SSPLL} can replace the voltage regulator.

16.2.5 V_{REGEN} — Optional Regulator Enable

This optional signal is used to shutdown VREG3V3V2. In that case V_{DD}/V_{SS} and V_{DDPLL}/V_{SSPLL} must be provided externally. Shutdown Mode is entered with V_{REGEN} being low. If V_{REGEN} is high, the VREG3V3V2 is either in Full Performance Mode or in Reduced Power Mode.

For the connectivity of V_{REGEN} see device overview chapter.

NOTE

Switching from FPM or RPM to shutdown of VREG3V3V2 and vice versa is not supported while the MCU is powered.

16.3 Memory Map and Register Definition

This subsection provides a detailed description of all registers accessible in VREG3V3V2.

16.3.1 Module Memory Map

Figure 16-2 provides an overview of all used registers.

Table 16-2. VREG3	V3V2 Memory	Мар
-------------------	-------------	-----

Address Offset	Use	Access
0x0000	VREG3V3V2 Control Register (VREGCTRL)	R/W

Chapter 17 16 Kbyte Flash Module (S12FTS16KV1)



In normal modes, all FABHI and FABLO bits read 0 and are not writable. In special modes, the FABHI and FABLO bits are readable and writable. For sector erase, the MCU address bits [8:0] are ignored. For mass erase, any address within the Flash array is valid to start the command.

17.3.2.10 Flash Data Register (FDATA)

FDATAHI and FDATALO are the Flash data registers.





In normal modes, all FDATAHI and FDATALO bits read 0 and are not writable. In special modes, all FDATAHI and FDATALO bits are readable and writable when writing to an address within the Flash address range.

17.3.2.11 RESERVED3

This register is reserved for factory testing and is not accessible to the user.



then FCLKDIV register bits PRDIV8 and FDIV[5:0] are to be set as described in Figure 17-21.

For example, if the oscillator clock frequency is 950 kHz and the bus clock is 10 MHz, FCLKDIV bits FDIV[5:0] should be set to 4 (000100) and bit PRDIV8 set to 0. The resulting FCLK is then 190 kHz. As a result, the Flash algorithm timings are increased over optimum target by:

 $(200 - 190)/200 \times 100 = 5\%$

Command execution time will increase proportionally with the period of FCLK.

CAUTION

Because of the impact of clock synchronization on the accuracy of the functional timings, programming or erasing the Flash array cannot be performed if the bus clock runs at less than 1 MHz. Programming or erasing the Flash array with an input clock < 150 kHz should be avoided. Setting FCLKDIV to a value such that FCLK < 150 kHz can destroy the Flash array due to overstress. Setting FCLKDIV to a value such that (1/FCLK + Tbus) < 5 μ s can result in incomplete programming or erasure of the Flash array cells.

If the FCLKDIV register is written, the bit FDIVLD is set automatically. If the FDIVLD bit is 0, the FCLKDIV register has not been written since the last reset. If the FCLKDIV register has not been written to, the Flash command loaded during a command write sequence will not execute and the ACCERR flag in the FSTAT register will set.



19.3.2 Register Descriptions

The Flash module contains a set of 16 control and status registers located between module base + 0x0000 and 0x000F. A summary of the Flash module registers is given in Figure 19-5. Detailed descriptions of each register bit are provided.

Register Name		Bit 7	6	5	4	3	2	1	Bit 0
0x0000 FCLKDIV	R W	FDIVLD	PRDIV8	FDIV5	FDIV4	FDIV3	FDIV2	FDIV1	FDIV0
0x0001	R	KEYEN1	KEYEN0	NV5	NV4	NV3	NV2	SEC1	SEC0
FSEC	W								
0x0002 RESERVED1 (1)	R W	0	0	0	0	0	0	0	0
0x0003 FCNFG	R W	CBEIE	CCIE	KEYACC	0	0	0	0	0
0x0004 FPROT	R W	FPOPEN	NV6	FPHDIS	FPHS1	FPHS0	FPLDIS	FPLS1	FPLS0
0x0005 FSTAT	R W	CBEIF	CCIF	PVIOL	ACCERR	0	BLANK	FAIL	DONE
0x0006	R	0	CMDB6	CMDB5	0	0	CMDB2	0	CMDB0
FCMD	W								
0x0007	R	0	0	0	0	0	0	0	0
	vv R								
FADDRHI ¹	W	_			FAI	3HI			
0x0008 FADDRHI ¹	R W	0				FABHI			
0x0009 FADDRLO ¹	R W				FAE	BLO			
0x000A FDATAHI ¹	R W				FD	НІ			
0x000B FDATAL O ¹	R W				FD	LO			
0x000C	R	0	0	0	0	0	0	0	0
RESERVED3 ¹	w								
0x000D	R	0	0	0	0	0	0	0	0
0x000E	R	0	0	0	0	0	0	0	0
RESERVED5 ¹	W								
0x000F RESERVED6 ¹	R W	0	0	0	0	0	0	0	0
		= Unimplemented or Reserved							

Figure 19-5. Flash Register Summary

1. Intended for factory test purposes only.



19.3.2.14 RESERVED6

This register is reserved for factory testing and is not accessible to the user.

Module Base + 0x000F



Figure 19-23. RESERVED6

All bits read 0 and are not writable.

19.4 Functional Description

19.4.1 Flash Command Operations

Write operations are used for the program, erase, and erase verify algorithms described in this section. The program and erase algorithms are controlled by a state machine whose timebase FCLK is derived from the oscillator clock via a programmable divider. The FCMD register as well as the associated FADDR and FDATA registers operate as a buffer and a register (2-stage FIFO) so that a new command along with the necessary data and address can be stored to the buffer while the previous command is still in progress. This pipelined operation allows a time optimization when programming more than one word on a specific row, as the high voltage generation can be kept active in between two programming commands. The pipelined operation allows a simplification of command launching. Buffer empty as well as command completion are signalled by flags in the FSTAT register with corresponding interrupts generated, if enabled.

The next sections describe:

- How to write the FCLKDIV register
- Command write sequence used to program, erase or erase verify the Flash array
- Valid Flash commands
- Errors resulting from illegal Flash operations

19.4.1.1 Writing the FCLKDIV Register

Prior to issuing any Flash command after a reset, it is first necessary to write the FCLKDIV register to divide the oscillator clock down to within the 150-kHz to 200-kHz range. Since the program and erase timings are also a function of the bus clock, the FCLKDIV determination must take this information into account.

If we define:

• FCLK as the clock of the Flash timing control block





Figure 19-25. Example Erase Verify Command Flow



Chapter 20 96 Kbyte Flash Module (S12FTS96KV1)

20.3.2.1 Flash Clock Divider Register (FCLKDIV)

The FCLKDIV register is used to control timed events in program and erase algorithms.





Figure 20-6. Flash Clock Divider Register (FCLKDIV)

All bits in the FCLKDIV register are readable, bits 6–0 are write once and bit 7 is not writable.

Table 20-4. FCLKDIV Field Descriptions

Field	Description
7 FDIVLD	 Clock Divider Loaded FCLKDIV register has not been written FCLKDIV register has been written to since the last reset
6 PRDIV8	 Enable Prescalar by 8 0 The oscillator clock is directly fed into the Flash clock divider 1 The oscillator clock is divided by 8 before feeding into the Flash clock divider
5–0 FDIV[5:0]	Clock Divider Bits — The combination of PRDIV8 and FDIV[5:0] must divide the oscillator clock down to a frequency of 150 kHz – 200 kHz. The maximum divide ratio is 512. Refer to Section 20.4.1.1, "Writing the FCLKDIV Register" for more information.

20.3.2.2 Flash Security Register (FSEC)

The FSEC register holds all bits associated with the security of the MCU and Flash module.

Module Base + 0x0001



Figure 20-7. Flash Security Register (FSEC)

All bits in the FSEC register are readable but not writable.

The FSEC register is loaded from the Flash configuration field at 0xFF0F during the reset sequence, indicated by F in Figure 20-7.



Chapter 20 96 Kbyte Flash Module (S12FTS96KV1)





Figure 21-17. RESERVED3

All bits read 0 and are not writable.

21.3.2.12 RESERVED4

This register is reserved for factory testing and is not accessible to the user.

Module Base + 0x000D



Figure 21-18. RESERVED4

All bits read 0 and are not writable.

21.3.2.13 RESERVED5

This register is reserved for factory testing and is not accessible to the user.

Module Base + 0x000E





All bits read 0 and are not writable.

21.3.2.14 RESERVED6

This register is reserved for factory testing and is not accessible to the user.



A.1.7 Operating Conditions

This chapter describes the operating conditions of the devices. Unless otherwise noted those conditions apply to all the following data.

NOTE

Instead of specifying ambient temperature all parameters are specified for the more meaningful silicon junction temperature. For power dissipation calculations refer to Section A.1.8, "Power Dissipation and Thermal Characteristics"

Rating	Symbol	Min	Тур	Max	Unit
I/O, Regulator and Analog Supply Voltage	V _{DD5}	2.97	5	5.5	V
Digital Logic Supply Voltage ⁽¹⁾	V _{DD}	2.35	2.5	2.75	V
PLL Supply Voltage ¹	V _{DDPLL}	2.35	2.5	2.75	V
Voltage Difference V _{DDX} to V _{DDA}	Δ_{VDDX}	-0.1	0	0.1	V
Voltage Difference V_{SSX} to V_{SSR} and V_{SSA}	$\Delta_{\sf VSSX}$	-0.1	0	0.1	V
Bus Frequency	f _{bus} (2)	0.25	—	25	MHz
Bus Frequency	f _{bus} (3)	0.25	_	16	MHz
Operating Junction Temperature Range	T	-40	_	140	°C

Table A-4. Operating Conditions

1. The device contains an internal voltage regulator to generate the logic and PLL supply out of the I/O supply. The operating conditions apply when this regulator is disabled and the device is powered from an external source. Using an external regulator, with the internal voltage regulator disabled, an external LVR must be provided.

2. Some blocks e.g. ATD (conversion) and NVMs (program/erase) require higher bus frequencies for proper operation.

3. Some blocks e.g. ATD (conversion) and NVMs (program/erase) require higher bus frequencies for proper operation.



Appendix A Electrical Characteristics

A.1.9 I/O Characteristics

This section describes the characteristics of all I/O pins. All parameters are not always applicable, e.g. not all pins feature pull up/down resistances.

Conditions are 4.5< V _{DDX} <5.5V Temperature from -40°C to +140°C, unless otherwise noted									
Num	С	Rating	Symbol	Min	Тур	Max	Unit		
1	Р	Input High Voltage	V _{IH}	0.65*V _{DD5}			V		
	Т	Input High Voltage	V _{IH}	_	_	V _{DD5} + 0.3	V		
2	Р	Input Low Voltage	V _{IL}	—	_	0.35*V _{DD5}	V		
	Т	Input Low Voltage	V _{IL}	V _{SS5} - 0.3	_		V		
3	С	Input Hysteresis	V _{HYS}		250	—	mV		
4	Ρ	Input Leakage Current (pins in high ohmic input mode) ⁽¹⁾ $V_{in} = V_{DD5}$ or V_{SS5}	l _{in}	_		1	μA		
5	с	Output High Voltage (pins in output mode) Partial Drive I _{OH} = -2mA	V _{OH}	V _{DD5} – 0.8	—	—	v		
6	Р	Output High Voltage (pins in output mode) Full Drive I _{OH} = -10mA	V _{OH}	V _{DD5} – 0.8	—	_	v		
7	с	Output Low Voltage (pins in output mode) Partial Drive I _{OL} = +2mA	V _{OL}	_		0.8	v		
8	Р	Output Low Voltage (pins in output mode) Full Drive I _{OL} = +10mA	V _{OL}	_	—	0.8	v		
9	Р	Internal Pull Up Device Current, tested at V _{IL} Max.	I _{PUL}	_	_	-130	μA		
10	с	Internal Pull Up Device Current, tested at V _{IH} Min.	I _{PUH}	-10	_	_	μA		
11	Р	Internal Pull Down Device Current, tested at V _{IH} Min.	I _{PDH}	_	_	130	μA		
12	с	Internal Pull Down Device Current, tested at V _{IL} Max.	I _{PDL}	10	_	_	μA		
13	D	Input Capacitance	C _{in}	—	7	_	pf		
14	т	Injection current ⁽²⁾ Single Pin limit Total Device Limit. Sum of all injected currents	I _{ICS} I _{ICP}	2.5 25	_	2.5 25	mA		
15	Р	Port P, J Interrupt Input Pulse filtered ⁽³⁾	t _{PIGN}	—	—	3	μs		
16	Р	Port P, J Interrupt Input Pulse passed ³	t _{PVAL}	10	_	_	μs		

Table A-6. 5V I/O Characteristics

1. Maximum leakage current occurs at maximum operating temperature. Current decreases by approximately one-half for each 8 C to 12 C in the temperature range from 50 C to 125 C

2. Refer to Section A.1.4, "Current Injection", for more details

3. Parameter only applies in STOP or Pseudo STOP mode.